



Title of Change:	Test Change from 3mV to 9mV for NCS37013MNTWG		
Effective date:	21 November 2016		
Contact information:	Contact your local ON Semiconductor Sales Office or <Tamara.Olney@onsemi.com>		
Type of notification:	ON Semiconductor will consider this change accepted.		
Change category:	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____		
Change Sub-Category(s):			
<input type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change		<input type="checkbox"/> Material Change <input type="checkbox"/> Product specific change	
		<input checked="" type="checkbox"/> Datasheet/Product Doc change <input checked="" type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____	
Sites Affected:			
<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input checked="" type="checkbox"/> ON Semiconductor site(s) : ON Pocatello, Idaho ON Carmona, Philippines			
<input type="checkbox"/> External Foundry/Subcon site(s)			
Description and Purpose:			
Update CTstim Offset Voltage limit at both wafer sort and final test to +/-9 mV. Mark change is to add a dash to differentiate between 3mV and 9mV per customer request.			
List of affected Standard Parts:			
NCS37013MNTWG			